Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/702,081	TAKANO ET AL.
Examiner	Art Unit

Mark A. Chapman

1756

	SEARCHED				
Class	Subclass	Date	Examiner		
430	111.1	10/31/2005	мс		
	111.4				
	108.1				
399	252				

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
111.1	10/31/2005	МС	
111.4		-	
108.1			
-			
	Subclass 111.1 111.4	Subclass Date 111.1 10/31/2005 111.4 10/31/2005	

SEARCH NOT (INCLUDING SEARCH	STRATEGY)
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east	10/31/2005	МС
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